DOCUMENT CHANGE REQUEST

DCR number 1156

Changes required for: General

Originator: Steve Thacker

Date: 2018/10/29

Date sent: 2018/04/09

Organisation: ESCC Executive Secretariat

Status: IMPLEMENTED

Title:	Transistors, Microwave, Small Signal, Silicon, Bipolar, based on Type BFY740B		
Number:	5611/011	Issue:	3

Other documents affected:

Page:

See attachment 5611/011 Draft 4B

Paragraph:

See below and in attachment 5611/011 Draft 4B

Original wording:

See 5611/011 issue 3

Proposed wording:

The following changes are proposed as detailed (highlighted yellow) in the attachment:
ESCC5611011 Draft 4B in review.docx:

A) Various minor editorial changes are implemented as highlighted in the attachment.

B) Para 1.4.2: add new Variant 02 with different die metallisation compared to Variant 01 (Die Metallisation column is also added to table)

C) Para 2.1.1: Add new deviation on Radiographic Inspection during Screening Tests.

D) Para 2.5.1 Characteristic ICEX: new limits are added for new Variant 02.

Justification:

The technical changes included above (points B C D) are as proposed by ESCC Qualified Manufacturer Infineon.

Attachments:
escc5611011_draft_4b_in_review.docx
Modifications:
N/A
Approval signature:
Date signed:
2018-10-29